

Special Section : LSI Design Techniques under Increase of Device Variations in CMOS Scaling

- Editorial Preface Hiroki ISHIKURO 415
1. Variability of Characteristics in Scaled MOSFETs
Toshiro HIRAMOTO, Kiyoshi TAKEUCHI, and Akio NISHIDA 416
2. Effect of Variations of MOSFETs on SRAM Performance and Techniques to Handle MOSFET Variations
Masanao YAMAOKA 427
3. Digital LSI Design under Device Variations Masahiro NOMURA 433
4. Design Automation Techniques Considering Process Variability Shuji TSUKIYAMA 440
5. Impacts and Countermeasures in Device Mismatches in Analog Circuits Shiro DOSHO 446

Technical Survey

- International Standardization and Business Strategy : A Special Session at IEICE Society Conference 2008
Hiroshi TANAKA 452
- Human Interface Using Acoustic Waves Masao TAKEUCHI 458

Lecture Series

- Optimization Computation for 3-D Understanding of Images [Ⅲ] : Fundamental Matrix Computation
Yasuyuki SUGAYA and Kenichi KANATANI 463

Memoirs

- Behind the ISS History : Great Contribution of Mr. Switching, Amos E. Joel, Jr.
Kohei HABARA 469

News Analysis

- System-level Operation of 3D Integration of Processor and SRAM by Using Inductive-coupling Links 472
- Prototype of Symmetric 10G-EPON System with Bidirectional 10Gbit/s Optical Access Allowing Coexistence with 1G-EPON ONUs 473

Technical Report

- E-Society Software Development Project for Speech Recognition and Synthesis
Kiyohiro SHIKANO, Kazuya TAKEDA, Tatsuya KAWAHARA, Hideki KAWAHARA, Hiroshi SARUWATARI, Keiichi TOKUDA, Akinobu LEE, Hiromichi KAWANAMI, Ryuichi NISIMURA, Randy GOMEZ, Tomoki TODA, Takanobu NISHIURA, Toru TAKAHASHI, Hideki BANNO, and Heiga ZEN 475